





APPROVAL SHEET

Dielectric Chip Antenna

Part No : AMAN802012PT07

Modle : PC-8200N


2006. 3. 17

AMOTECH Co., Ltd 5B-1L, 617, Namchon-Dong, Namdong-Gu, Incheon, KOREA. TEL : 82-32-821-0363 FAX : 82-32-811-0283	Written	Checked		Approved
				

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1. Revision Record

Date	Content	Page
2006. 3. 17	NEW	

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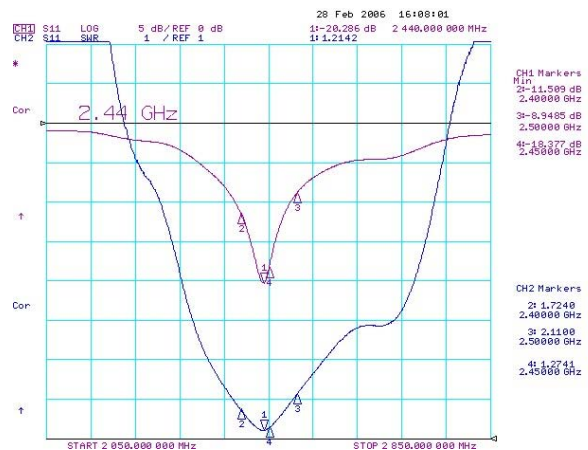
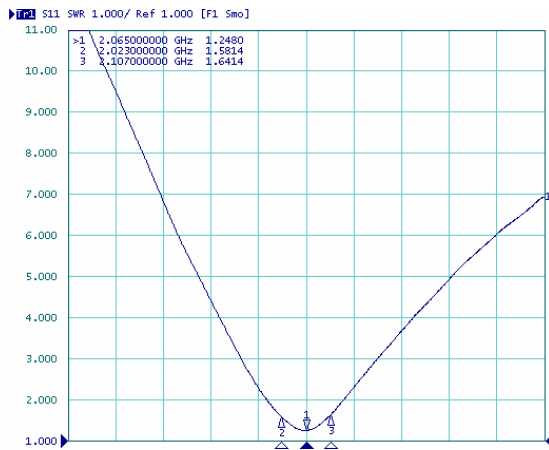
2. SPECIFICATIONS


2.1 Electrical Specification

No	ITEM	Spec		Remark	
1	VSWR	Max 5.0 : 1 @ 2065±42MHz			
2	Radiation Gain	Avg.	H	Min -5.0	dBi
			E1	Min -3.5	
			E2	Min -3.5	
		Peak	H	Min -3.0	
			E1	Min -1.0	
E2	Min -1.0				
3	Radiation Pattern	Omni-directional			
4	Impedence	nominal 50		Ω	

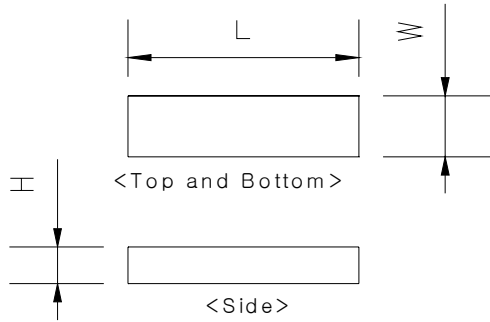
※ Radiation Pattern : measured data after matching on Bluetooth range

※ VSWR : measured data on manual jig



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2.2 Mechanical Specification



L (Length)	8.0
W (Width)	2.0
H (Height)	1.2


- unit : mm
- Tolerance : ± 0.15

2.3 Model & Lot notation

Model : AMAN 802012 PT 07
 (1) (2) (3) (4)

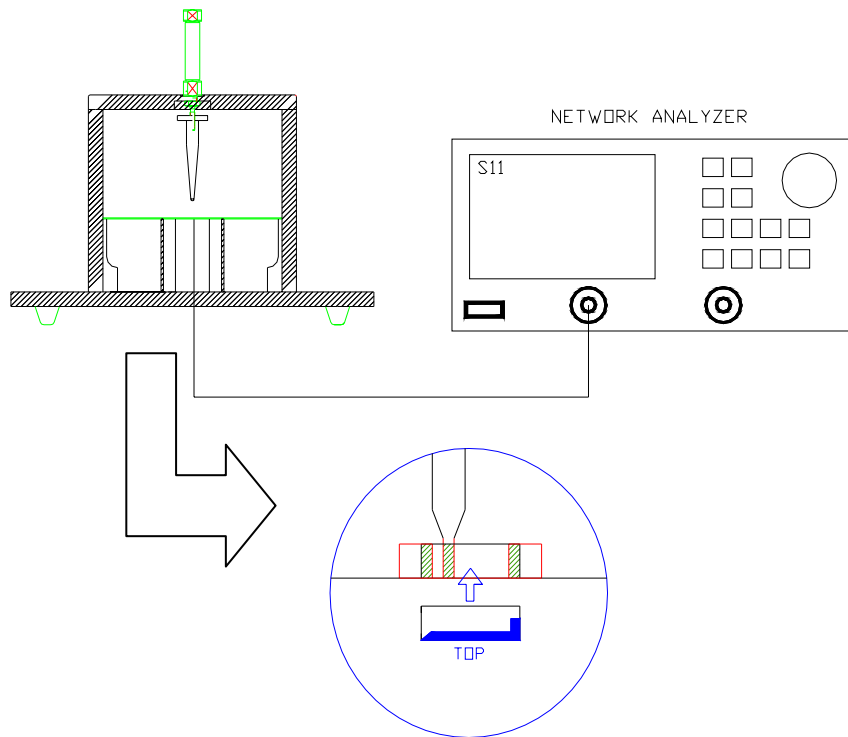
- (1) : **AMOTECH ANTENNA**
- (2) : Chip Size (Length X Width X Height)
- (3) : Enterprise, Ex) PANTECH – PT
- (4) : Model Num. (Ex : 07-PN820)

Lot : XX XX X X XX
 (1) (2) (3) (4) (5)

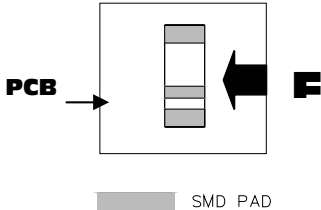
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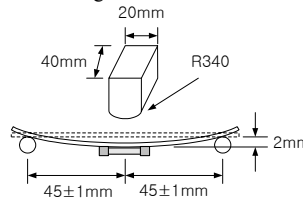
3. MEASUREMENT


3.1 VSWR's Measurement



4. RELIABILITY TEST

No	ITEM	TEST CONDITION	TEST REQUIREMENTS
1	Adhesion strength	1. Applied force on SMD chip till detached point from PCB. 	1. No mechanical damage by forces applied on the right. 2. Strength (F) > kgf

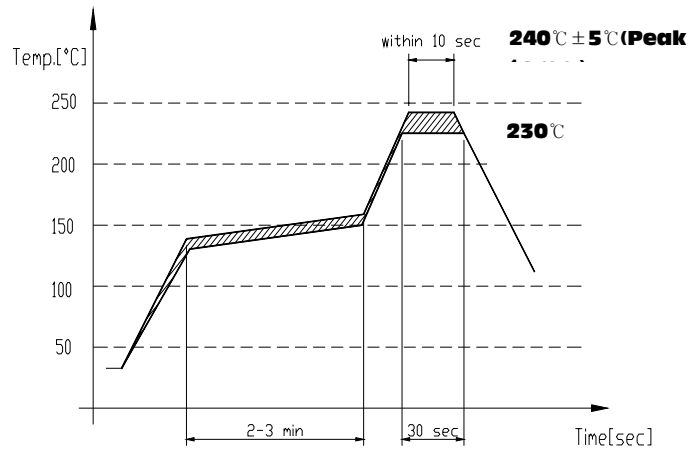
2	bending strength	<ol style="list-style-type: none"> 1. Flexural state: 2 mm 2. Speed: 0.5 mm/sec 3. lasting time: 5 sec 	<ol style="list-style-type: none"> 1. No mechanical damage by forces applied on the right.
3	Thermal shock	<ol style="list-style-type: none"> 1. 1 cycle / 1 step : -40 ± 3°C, 30 min 2 step : +125 ± 3°C, 30 min 2. Number of cycle : 30 3. Measure f_c after left for 48 hrs min. at room temperature 	<ol style="list-style-type: none"> 1. No visual damage 2. Within electric spec (VSWR)
4	High temp. resistance	<ol style="list-style-type: none"> 1. Temperature : +125 ± 5°C 2. Time : 1000 ± 24 hrs 3. Measure f_c after left for 48 hrs min. at room temperature 	<ol style="list-style-type: none"> 1. No visual damage 2. Within electric spec (VSWR)
5	Low temp. resistance	<ol style="list-style-type: none"> 1. Temperature : -40 ± 5°C 2. Time : 1000 ± 24 hrs 3. Measure f_c after left for 48 hrs min. at room temperature 	<ol style="list-style-type: none"> 1. No visual damage 2. Within electric spec (VSWR)
6	High temp. & humidity :Steady Condition	<ol style="list-style-type: none"> 1. Humidity : 85 % RH 1. Temperature : +85 ± 3°C 2. Time : 1000 ± 24 hrs 3. Measure f_c after left for 48 hrs min. at room temperature 	<ol style="list-style-type: none"> 1. No visual damage 2. Within electric spec (VSWR)
7	ESD	<ol style="list-style-type: none"> 1. ESD Level : 8KV 2. Mode : Contact discharge 3. Number of Test: 100 	<ol style="list-style-type: none"> 1. No visual damage 2. Within electric spec (VSWR)

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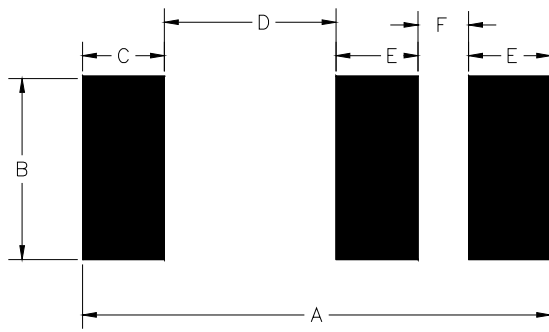
5. Soldering Recommendation

5.1 Soldering Profile

Solder paste : Ag/Sn/Cu:96.5/3.0/0.5




5.2 Soldering Land Pattern



UNIT : mm




A	8.0
B	2.0
C	1.0
D	4.2
E	1.0
F	0.8

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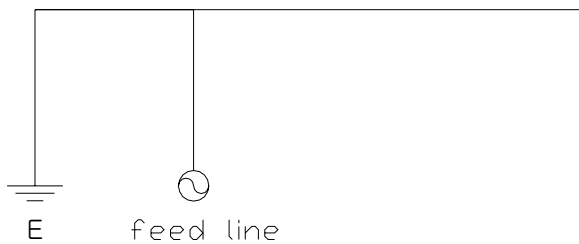
6. Structure & Material

6.1 Material




1	(Bulk)		Material
2	Pattern	 TOP	Ag
		 BOTTOM	
		 SIDE	

6.2 Equivalent circuit



7. Caution and Warranty

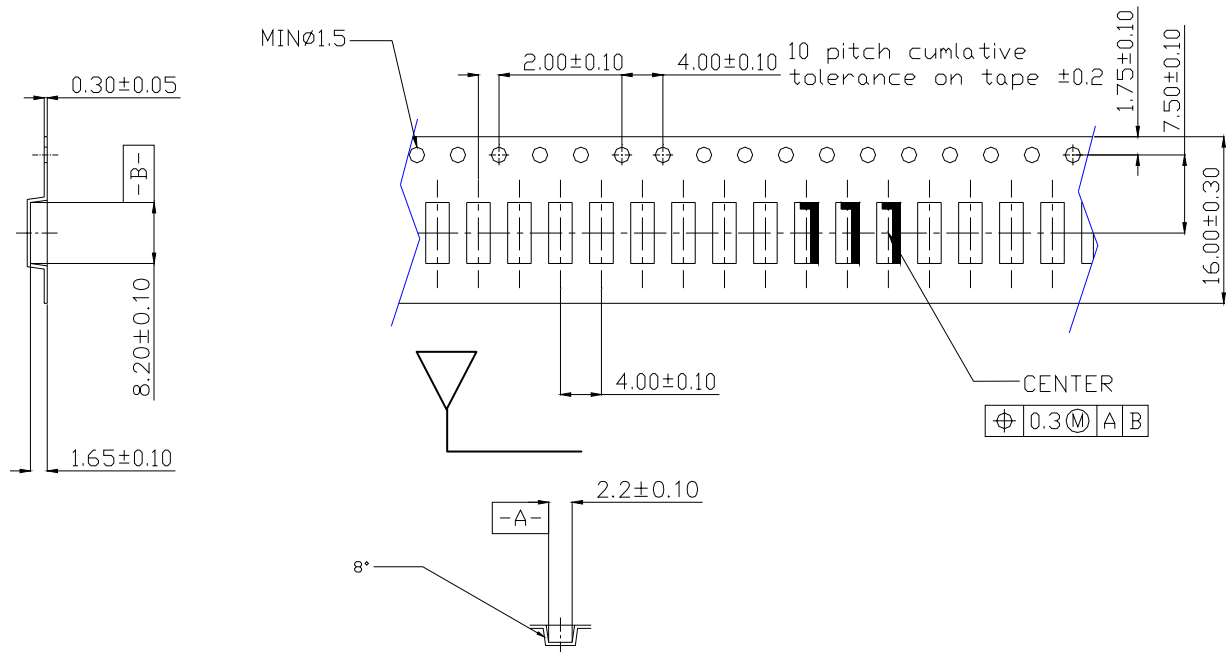
1. Ceramic Patch Antennas can be degraded when used at high temperature and humidity.
2. Electrode metallization made from silver is unprotected and will tarnish during storage in normal atmospheres affected by sulphuric compounds but has no effect whatsoever on the electrical performance or the processability of the patches. Because of this normal and to be expected process, AMOTECH accepts no warranty claims for tarnished products.
3. Ceramic Patch Antennas must avoid shock and drop, to prevent crack of antenna due to weight of itself.
4. Ceramic Patch Antennas must be used within 6 months, the antenna produced before 6 months should be checked for soldering feature before using


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8. Packing

8.1 Tape Dimension (unit : mm)

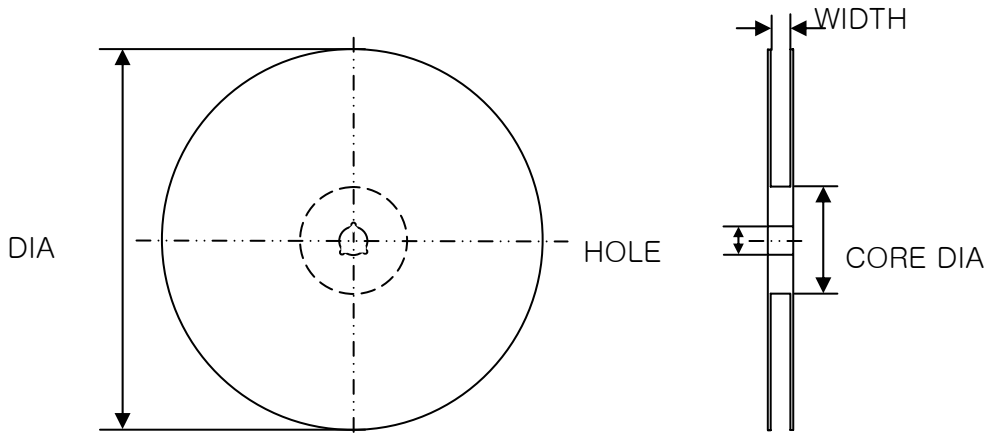
8.1.1 Size



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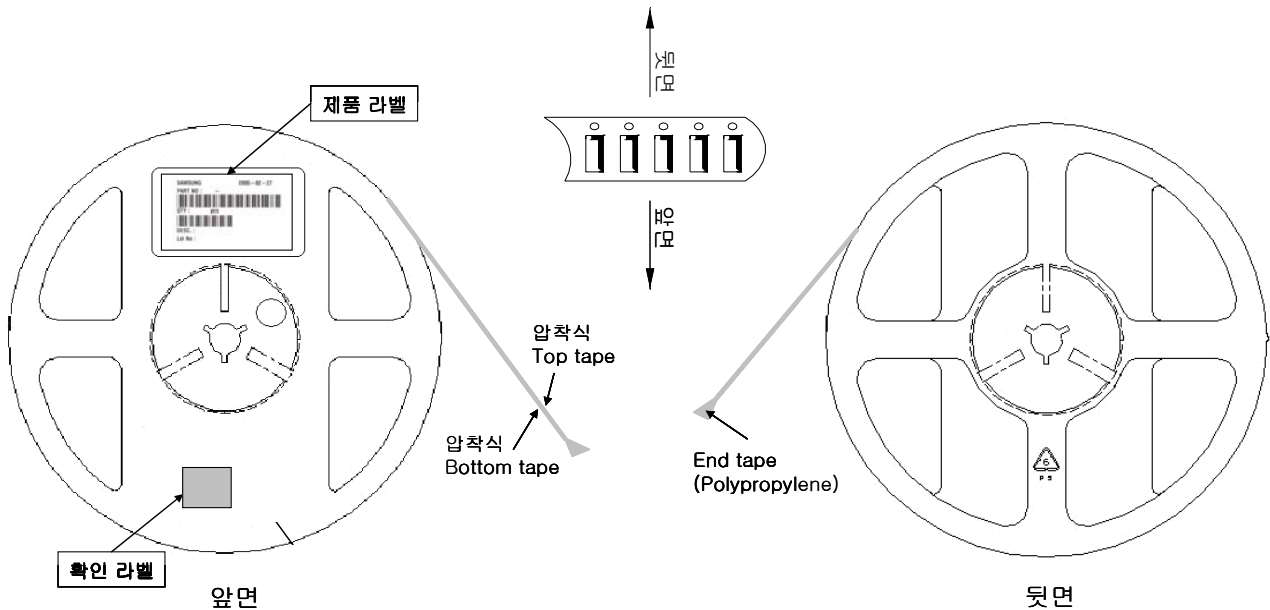
8.2 Description of Reel

8.2.1 Size




ITEM	DIA	WIDTH	CORE DIA	HOLE
Size(mm)	180.0 +0, -3	17.0 ± 0.3	60.0 ± 1	13.0 ± 0.5

8.2.2 Attaching Label & Winding Method



8.2.3 Material

- 1) Plastic reel : GPPS (General Purpose Poly Styrene) resin

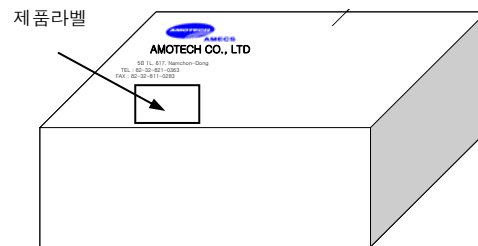
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8.3 Description of Packing Box

8.3.1 Small Box

Size : 185 (W) x 185 (D) x 68 (T) (mm)

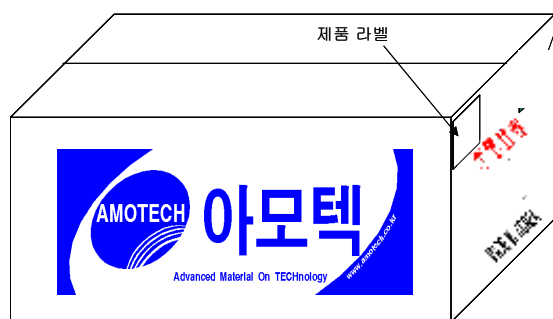
quantity : 3 reel (2,000 ea/reel × 3 reel = 6,000 ea)



8.3.2 Medium Box

Size : 365 (W) x 200 (D) x 200 (T) (mm)

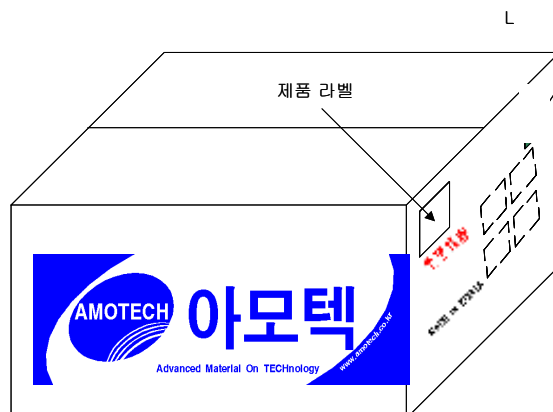
quantity : 5 Small Box (6,000 ea/ Small Box × 5 Small Box = 30,000 ea)




8.3.3 Large Box

Size : 390 (W) x 390 (D) x 280 (T) (mm)

quantity : 14 Small Box (6,000 ea/ Small Box × 14 Small Box = 84,000 ea)



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8.4 Description of Packing Label

AMOTECH CO.,LTD.


617 5B-1L, Namchon-Dong, Namdong-Gu, Incheon-City, Korea

Dielectric Chip Antenna

Type : AMAN802012PT07

Lot No :

Quantity : 2 000 pcs Date :

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9. Harmfulness material' s Test Report

9.1 Material ngredient Analysis

SGS Testing Korea Co., Ltd.
 #18-34, Sanbon-dong, Gunpo-city, Kyunggi-do, Korea 435-040
 Tel : 031) 428-5765-6, Fax: 031) 427-2374, InterNet>http://www.sgslab.co.kr

Test Report No. F690501/LF-CTS050284 Date : May 12, 2005 Page 1 of 2


AMOTECH
 617, Namchon-dong, Namdong-gu,
 Incheon, Korea

The following merchandise was submitted and identified by the client as :-

Type of Product : Ceramic PIFA Antenna
 SGS File No. : G-49/2005-2072/9
 Buyer : SAMSUNG
 Style / Item No. : Ceramic PIFA Antenna
 Sample Receiving Date : May. 04, 2005
 Test Performing Date : May. 06, 2005

Test Performed : SGS Testing Korea tested the sample which was selected by applicant with following result.

Test Results : For further details, please refer to following page.

SGS Testing Korea Co., Ltd.

 Jason Han / Director

KHJ/hjp

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DIELECTRIC CHIP ANTENNA

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SGS Testing Korea Co., Ltd.

#18-34, Sanbon-dong, Gunpo-city, Kyunggi-do, Korea 435-040
 Tel : 031) 428-5765-6, Fax: 031) 427-2374, InterNet>http://www.sgslab.co.kr

Test Report No. F690501/LF-CTS050284 Date : May 12, 2005 Page 2 of 2

Heavy Metal

Test Items	Unit	Test Method	MDL	Results
Cadmium (Cd)	mg/kg	USEPA 3050B, ICP-AES	0.5	n. d.
Lead (Pb)	mg/kg	USEPA 3050B, ICP-AES	5	n. d.
Mercury (Hg)	mg/kg	USEPA 3052, ICP-AES	2	n. d.
Hexavalent Chromium (Cr VI)	mg/kg	USEPA 3060A, UV-vis	1	n. d.


Flame Retardants

Test Items	Unit	Test Method	MDL	Results
Polybrominated Biphenyls (PBBs)	-	-	-	-
Bromobiphenyl	mg/kg	With reference to USEPA 3540C. Analysis was performed by GC/MS..	5	n. d.
Dibromobiphenyl	mg/kg		5	n. d.
Tribromobiphenyl	mg/kg		5	n. d.
Tetrabromobiphenyl	mg/kg		5	n. d.
Pentabromobiphenyl	mg/kg		5	n. d.
Hexabromobiphenyl	mg/kg		5	n. d.
Heptabromobiphenyl	mg/kg		5	n. d.
Octabromobiphenyl	mg/kg		5	n. d.
Nonabromobiphenyl	mg/kg		5	n. d.
Decabromobiphenyl	mg/kg		5	n. d.
Polybrominated Diphenyl Ethers (PBDEs)	-	-	-	-
Bromodiphenyl ether	mg/kg	With reference to USEPA 3540C. Analysis was performed by GC/MS.	5	n. d.
Dibromodiphenyl ether	mg/kg		5	n. d.
Tribromodiphenyl ether	mg/kg		5	n. d.
Tetrabromodiphenyl ether	mg/kg		5	n. d.
Pentabromodiphenyl ether	mg/kg		5	n. d.
Hexabromodiphenyl ether	mg/kg		5	n. d.
Heptabromodiphenyl ether	mg/kg		5	n. d.
Octabromodiphenyl ether	mg/kg		5	n. d.
Nonabromodiphenyl ether	mg/kg		5	n. d.
Decabromodiphenyl ether	mg/kg		5	n. d.


Note : n. d. = Not detected
 MDL = Method Detection Limit

***** End *****

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9.2 Powder



Test Report

FUJII TITANIUM IND. CO., LTD. Report No. : CE/2004/61738
 12-8, SENGUN-CHO, HIRATSUKA-CITY, Date : 2004/06/21
 KANAKAWA-PREF. JAPAN Page : 1 of 1

The following merchandise was (were) submitted and identified by the client as :


Type of Product : BARIUM TITANATE POWDER
Style/Item No : MMT-20M(E)
Sample Received : 2004/06/15
Testing Date : 2004/06/15 TO 2004/06/21

Test Result

PART NAME NO.1 : GRAY POWDER

Test Item (s)	Unit	Method	MDL	Result			
				No.1			
Cadmium (Cd)	ppm	ICP-AES after as per EN 1122, method B-2001 or other acid digestion.	2	N.D.			
Chromium (Cr)	ppm	ICP-AES after as per US EPA 3050B or other acid digestion.	2	N.D.			
Mercury (Hg)	ppm	ICP-AES after as per US EPA 3052 or other acid digestion.	2	N.D.			
Lead (Pb)	ppm	ICP-AES after as per US EPA 3050B or other acid digestion.	2	N.D.			


NOTE: (1) N.D. = Not detected (<MDL)
 (2) ppm = mg/kg
 (3) MDL = Method Detection Limit


 Daniel Yeh, M.S., Operation Manager
 Signed for and on behalf of
 SGS TAIWAN LTD.

TW0883088

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200 Yungping Rd. | No. 1281 Wu-Kuang Road, Wu-Kuang Industrial Zone, Taipei County, Taiwan. / 台北市五股區五工路128-1號
 台灣檢驗科技股份有限公司 | 11085 21 2298-2600 | 8865-21 2298-2222 | www.sgs.com

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9.3 Ag paste

SGS

Test Report No. F690501/LF-CTSGP06-0257 **Date:** January 11, 2006 **Page 1 of 2**

To: MICRO M CO., LTD.
Rm#503, B-dong, Bundangtechnopark
Yatap-dong
Bundang-gu
KYUNGKI-DO
Korea

The following merchandise was submitted and identified by the client as :

Commodity : PCC11837
SGS File No. : GP06-0257
Received Date : January 04, 2006
Test Performing Date : January 05, 2006
Test Performed : SGS Testing Korea tested the sample(s) selected by applicant with following results
Test Results : For further details, please refer to following page(s)
Buyer(s) : SAMSUNG

Brendan Lee
Patrick An
Monet Jeong
Jinee Song
/Testing Person


Jeff Jang / Technical Mgr

SGS Testing Korea Co. Ltd.


Jason Han / Lab Director

The above certificate is the accredited test items by Korea Laboratory Accreditation Scheme (KOLAS), which signed the ILAC-MRA.

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Test Report No. F690501/LF-CTSGP06-0257

Date: January 11, 2006

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Sample No. : GP06-0257.001
Sample Description : PCC11837
Style/item No. : N/A
Comments : Material is silver paste.

Heavy Metals

Test Items	Unit	Test Method	MDL	Results
Cadmium (Cd)	mg/kg	US EPA 3050B(1996), US EPA 6010B(1996)	0.5	N.D.
Lead (Pb)	mg/kg	US EPA 3050B(1996), US EPA 6010B(1996)	5	12.0
Mercury (Hg)	mg/kg	US EPA 3052(1996), US EPA 6010B(1996)	2	N.D.
Hexavalent Chromium (Cr VI)	mg/kg	US EPA 3060A(1996), US EPA 7196A(1992)	1	N.D.

Picture of Sample as Received:




*** End ***


NOTE: (1) N.D. = Not detected. (<MDL)
 (2) ppm = mg/kg
 (3) MDL = Method Detection Limit
 (4) Estimated expanded uncertainty U with a coverage factor =2, k corresponding to a level of confidence of about 95%

The above certificate is the accredited test items by Korea Laboratory Accreditation Scheme (KOLAS), which signed the ILAC-MRA.

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9.4 Carrier Tape



SGS Korea Co., Ltd.
#1002-2, Hwasan-ri, Onsan-ub, Ulju-gun, Ulsan, Korea 689-890
Tel : 052)239-6908~10, Fax: 052)239-6913, InterNet>http://www.sgsgroup.co.kr

Test Report No. F690101/LF-CTS008578 Date : December 19, 2003 Page 1 of 2

CHEM TECH SOLUTION CO., LTD
#402 Najin Bldg., 408, Sang-dong, Wonmi-gu, Bucheon-si,
Gyeonggi-do, Korea

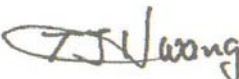
The following merchandise was submitted and identified by the client as : -

Type of Product : PS Clear Sheet
SGS File No. : S-49/2003-4761
Country of Origin : Korea
Sample Receiving Date : Dec. 11, 2003
Test Performing Date : Dec. 12, 2003

Test Performed : SGS Korea tested the sample which was selected by applicant with following result.

Test Results : For further details, please refer to following page.

SGS Korea Co., Ltd.




T.J.Hwang / Lab. Manager

SBP/mss

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Member of SGS Group (Société Générale de Surveillance)

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SGS

SGS Korea Co., Ltd.

#1002-2, Hwasan-ri, Onsan-ub, Ulju-gun, Ulsan, Korea 689-890
 Tel : 052)239-6908-10, Fax: 052)239-6913, InterNet>http://www.sgsgroup.co.kr

Test Report

No. F690101/LF-CTS008578

Date : December 19, 2003

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Heavy Metal

Test Item	Unit	Test Method	Detection Limit	Result
Cadmium (Cd)	mg/kg	EN 1122, ICP-AES	0.5	n. d.
Lead (Pb)	mg/kg	USEPA 3050B, ICP-AES	5	n. d.
Mercury (Hg)	mg/kg	USEPA 3052, ICP-AES	0.5	n. d.
Hexavalent Chromium (Cr VI)	mg/kg	USEPA 3060A	0.16	n. d.

Note : n. d. = Not detected


***** End *****

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SGS Korea Co., Ltd. | #1002-2, Hwasan-ri, Onsan-ub, Ulju-gun, Ulsan, Korea 689-890 t +82 52 239 6908-10 f +82 52 239 6913 www.sgsgroup.co.kr www.sgs.com

101

Member of SGS Group (Société Générale de Surveillance)

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9.5 Carrier Cover


DENKA
DENKA BUNSEKI CENTER
 8-6-1 Asahi-cho
 Machida-shi Tokyo 194-8660 JAPAN
 Phone : +81-42-721-3615
 Registry Number for Measurement Laboratory Accreditation
 of Tokyo metropolitan:541

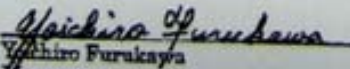
Laboratory Analysis Report

Report Date : April 22, 2004
 Doc. No. : 24016-4
 Sample Description : ALS-ATA
 Prepared for : OJIMA Plant DENKA KAKO CO.,LTD.

Results of Analysis

Analyte	Concentration/ppm	Method	Notes
Cadmium (Cd)	< 5ppm	SONY TECHNICAL STANDARDS SS-00259	
Chromium (Cr)	< 5ppm	SONY TECHNICAL STANDARDS SS-00259	Total Chromium
Lead (Pb)	< 30ppm	SONY TECHNICAL STANDARDS SS-00259	
Mercury (Hg)	< 2ppm	Japanese Clinical Standard	

Equipment for Measurement
 Cd,Pb,Cr : ICP-AES(Inductively Coupled Plasma Atomic Emission Spectrometer)
 Spector-RIKAKU Corp. CIROS-120
 Hg : Au-Amalgam Reduction - Atomic Absorption Spectrometer
 Nippon Instruments Corporation, MA-2000


 Naichiro Furukawa
 Manager